



MAIL STOP AF  
PATENT  
8053-1016

**IN THE U.S. PATENT AND TRADEMARK OFFICE**

In re application of

Kazuhiro NAKAJIMA et al. Conf. 9942

Application No. 10/625,695 Group 2811

Filed July 24, 2003 Examiner Ori Nadav

PRODUCTION PROCESS FOR PRODUCING  
SEMICONDUCTOR DEVICES, SEMICONDUCTOR  
DEVICES PRODUCED THEREBY, AND TEST  
SYSTEM FOR CARRYING OUT YIELD-RATE  
TEST IN PRODUCTION OF SUCH  
SEMICONDUCTOR DEVICES

**AMENDMENT AFTER FINAL REJECTION**

Assistant Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

November 3, 2006

Sir:

In response to the Official Action mailed May 9, 2006,  
please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing  
of claims which begins on page 2 of this paper.

**Remarks** begin on page 9 of this paper.

OK to enter

ON. n/a/06